

# NEW RELEASE SPIP™ 6.4 !

- increased efficiency, advanced image processing and analysis.

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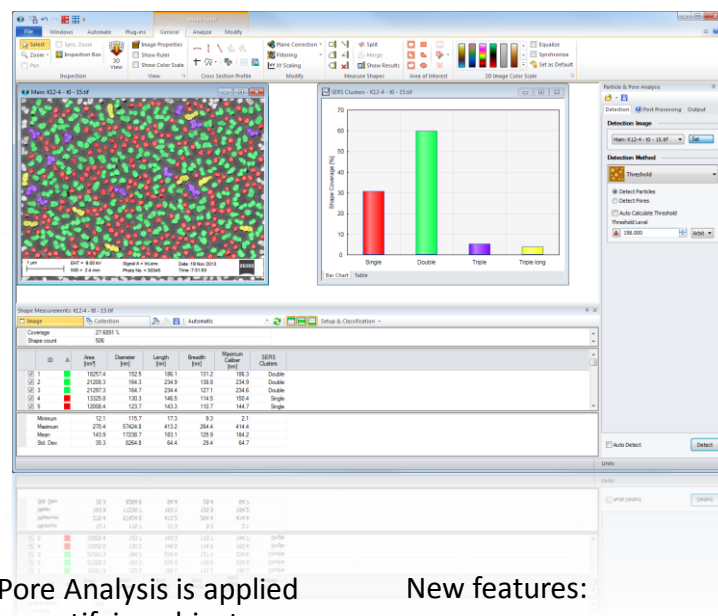
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## Introducing Particle Classification in SPIP™ 6.4



Classification in Particle & Pore Analysis

**SPIP™ Particle & Pore Analysis** is applied for detecting and quantifying objects differing from the surface substrate, e.g. particles, grains, surface defects, contamination, pits, cells, etc.

With the new classification tools, detected particles and pores can be grouped into different classes. New compelling charts can visualize the results. Reports for series of images are easily generated.

New features:

- Classification editor – a new interactive tool
- Simple and easy classification of single-parameters
- Advanced multi-parameter classification
- Class coloring in bar chart and in image
- Fiber profile analysis

Campaign offer valid until December 31, 2015